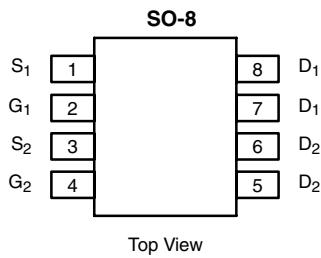


# Dual N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY				
	V <sub>DS</sub> (V)	r <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ)
N-Channel	40	0.039 at V <sub>GS</sub> = 10 V	6.6	6.6
		0.050 at V <sub>GS</sub> = 4.5 V	5.8	



Ordering Information: Si4906DY-T1-E3 (Lead (Pb)-free)

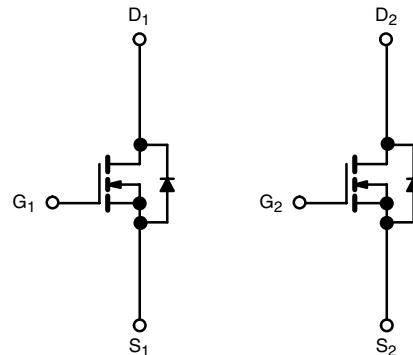
## FEATURES

- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS tested



## APPLICATIONS

- CCFL Inverter



N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T <sub>A</sub> = 25 °C, unless otherwise noted			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	40	V
Gate-Source Voltage	V <sub>GS</sub>	± 16	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 25 °C	I <sub>D</sub>	6.6
	T <sub>C</sub> = 70 °C		5.3
	T <sub>A</sub> = 25 °C		5.3 <sup>b, c</sup>
	T <sub>A</sub> = 70 °C		4.2 <sup>b, c</sup>
Pulsed Drain Current (10 µs Pulse Width)	I <sub>DM</sub>	30	A
Source-Drain Current Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	2.5
	T <sub>A</sub> = 25 °C		1.7 <sup>b, c</sup>
Pulsed Source-Drain Current	I <sub>SM</sub>	30	
Single Pulse Avalanche Current	I <sub>AS</sub>	13	
Single-Pulse Avalanche Energy	E <sub>AS</sub>	8.5	mJ
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	3.1
	T <sub>C</sub> = 70 °C		2
	T <sub>A</sub> = 25 °C		2 <sup>b, c</sup>
	T <sub>A</sub> = 70 °C		1.28 <sup>b, c</sup>
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 50 to 150	°C

THERMAL RESISTANCE RATINGS			
Parameter	Symbol	Limit	Unit
		Typical	Maximum
Maximum Junction-to-Ambient <sup>b, d</sup>	R <sub>thJA</sub>	52	°C/W
Maximum Junction-to-Foot (Drain)	R <sub>thJF</sub>	32	

Notes:

a. Based on T<sub>C</sub> = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 sec.

d. Maximum under Steady State conditions is 110 °C/W.

**SPECIFICATIONS**  $T_J = 25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ <sup>a</sup>	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		40		
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 4.6		
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.8		2.2	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$			100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			10	
On-State Drain Current <sup>b</sup>	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			A
Drain-Source On-State Resistance <sup>b</sup>	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		0.032	0.039	$\Omega$
		$V_{GS} = 4.5 \text{ V}, I_D = 4 \text{ A}$		0.041	0.050	
Forward Transconductance <sup>b</sup>	$g_{fs}$	$V_{DS} = 15 \text{ V}, I_D = 5 \text{ A}$		15		S
<b>Dynamic<sup>a</sup></b>						
Input Capacitance	$C_{iss}$	N-Channel $V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		625		pF
Output Capacitance	$C_{oss}$			88		
Reverse Transfer Capacitance	$C_{rss}$			50		
Total Gate Charge	$Q_g$	N-Channel $V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		14.4	22	nC
Gate-Source Charge	$Q_{gs}$			6.6	10	
Gate-Drain Charge	$Q_{gd}$			1.6		
Gate Resistance	$R_g$			2.3		
Turn-On Delay Time	$t_{d(\text{on})}$	N-Channel $V_{DD} = 20 \text{ V}, R_L = 4 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		2.3	3.5	$\Omega$
Rise Time	$t_r$			9	15	ns
Turn-Off Delay Time	$t_{d(\text{off})}$			51	77	
Fall Time	$t_f$			21	32	
Turn-On Delay Time	$t_{d(\text{on})}$			6	10	
Rise Time	$t_r$	N-Channel $V_{DD} = 20 \text{ V}, R_L = 4 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		13	20	ns
Turn-Off Delay Time	$t_{d(\text{off})}$			85	128	
Fall Time	$t_f$			17	26	
				7	11	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Source-Drain Diode Current	$I_S$	$T_C = 25^\circ\text{C}$			2.5	A
Pulse Diode Forward Current <sup>a</sup>	$I_{SM}$				30	
Body Diode Voltage	$V_{SD}$	$I_S = 1.7 \text{ A}$		0.79	1.2	V
Body Diode Reverse Recovery Time	$t_{rr}$	N-Channel $I_F = 1.7 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		30	45	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			30	45	nC
Reverse Recovery Fall Time	$t_a$			17		ns
Reverse Recovery Rise Time	$t_b$			13		

Notes:

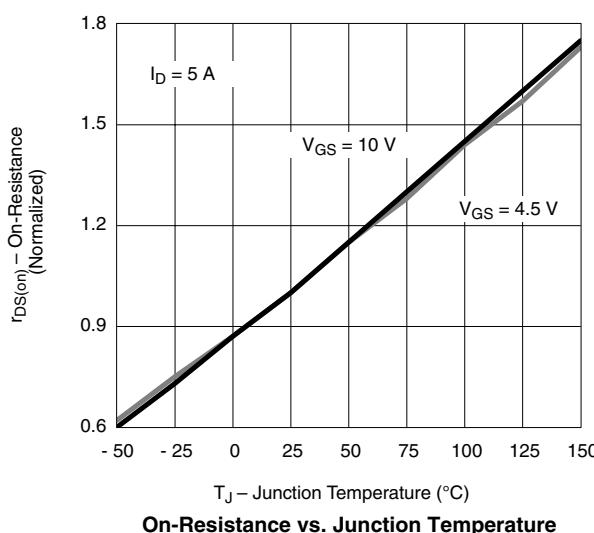
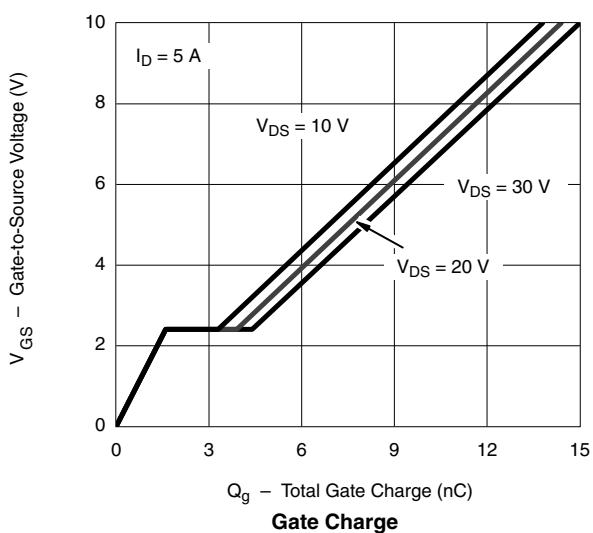
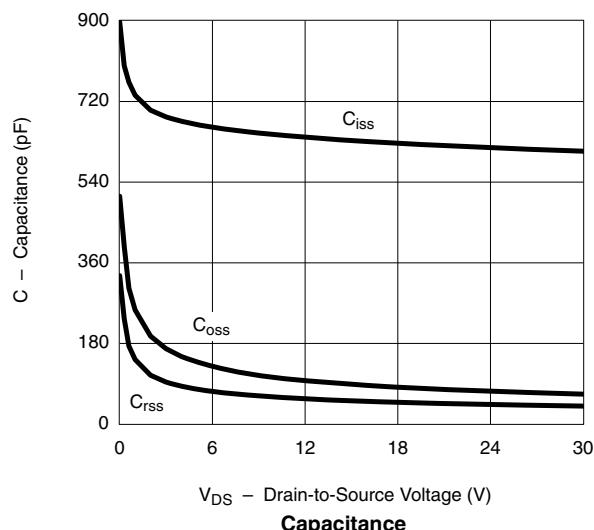
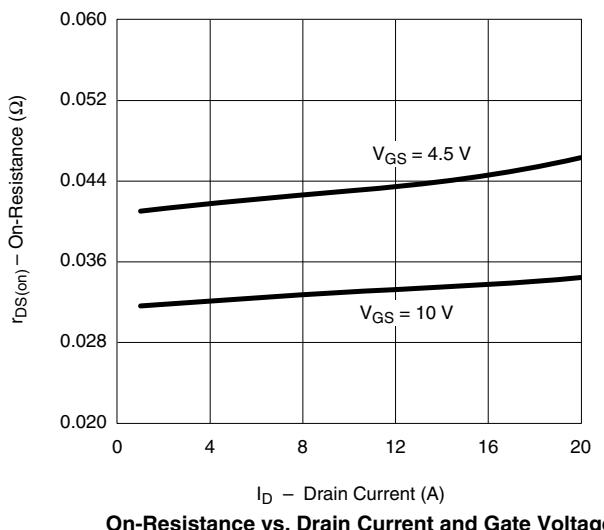
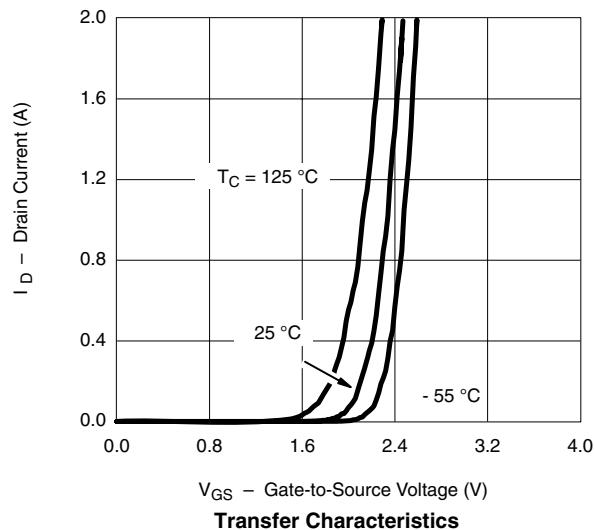
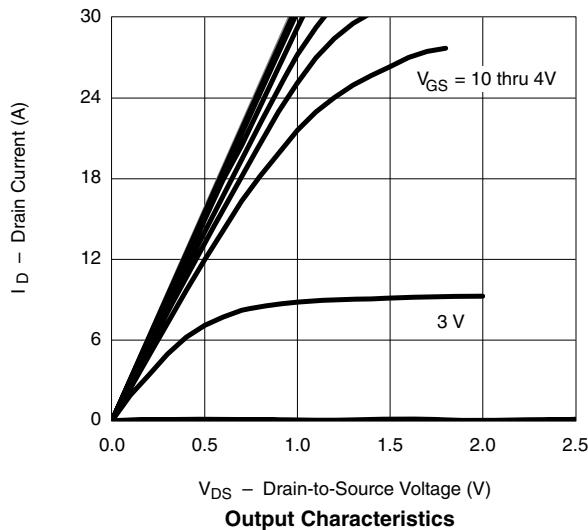
a. Guaranteed by design, not subject to production testing.

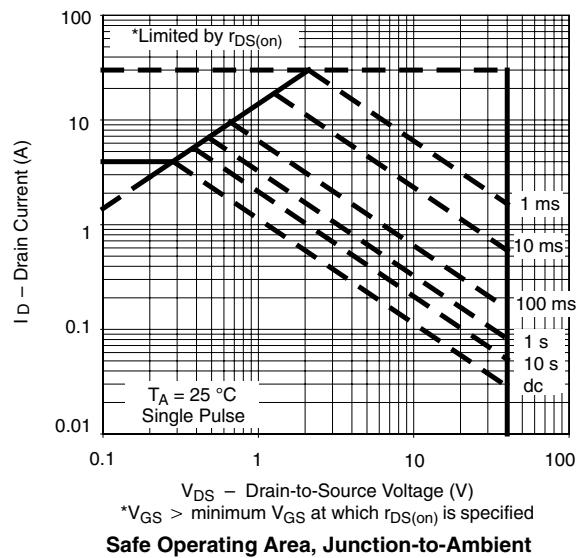
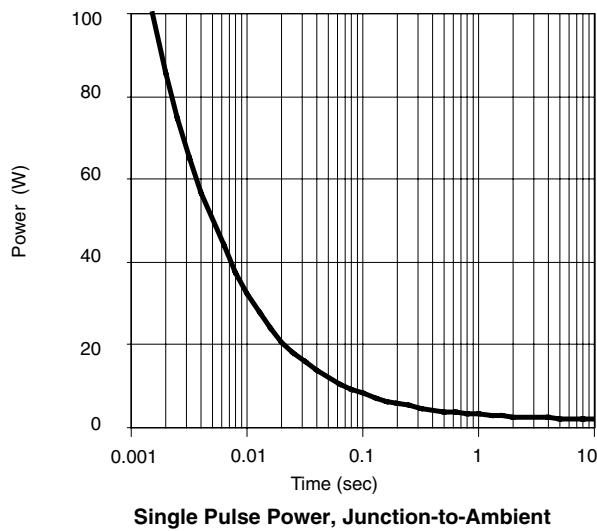
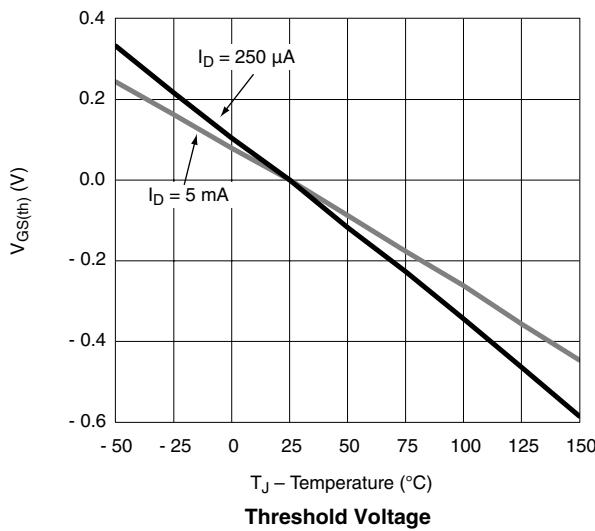
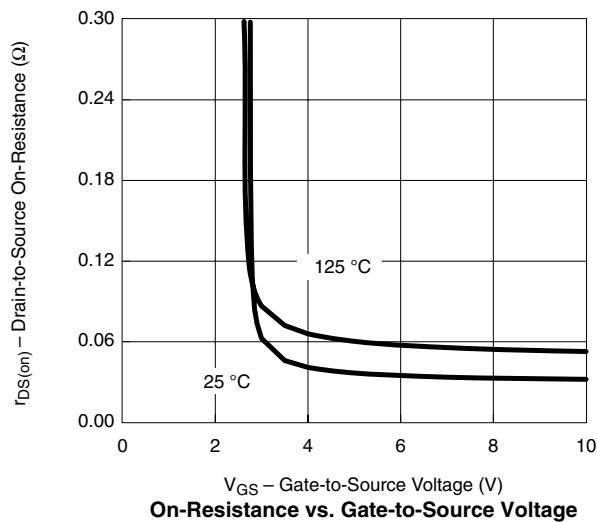
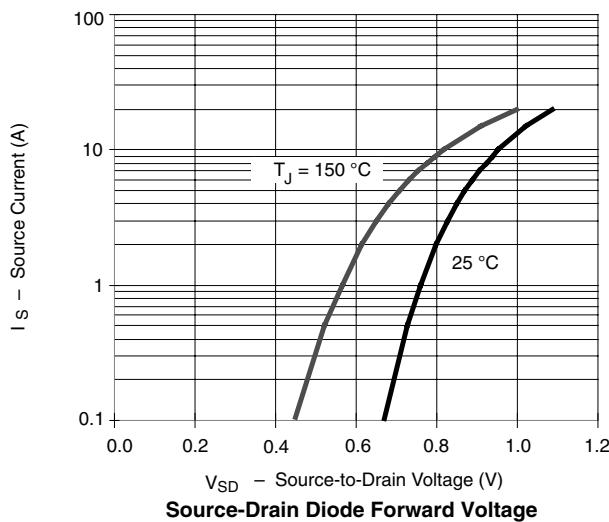
b. Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .

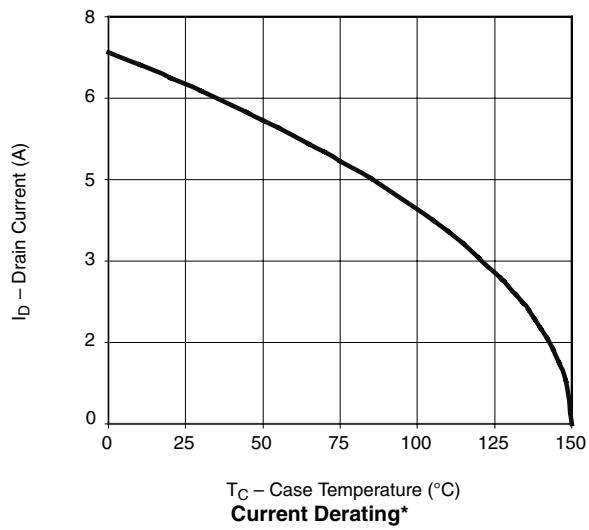
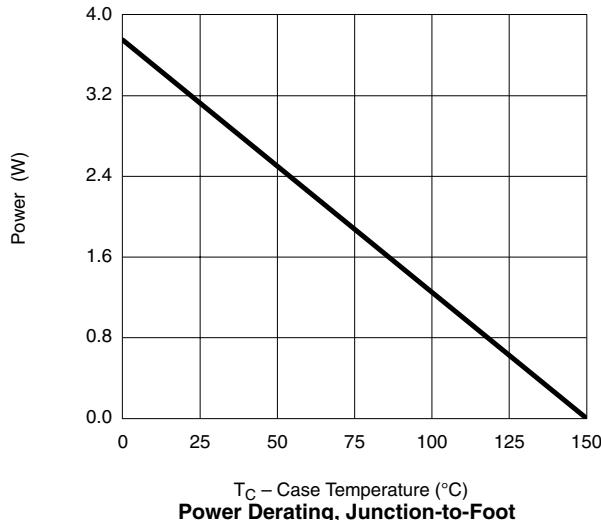
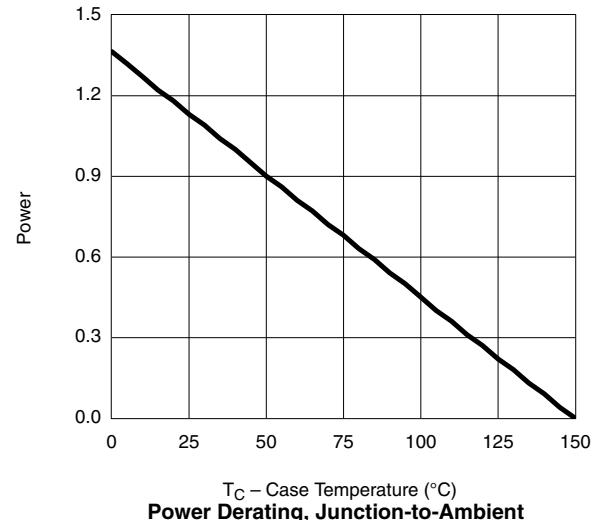
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**N-CHANNEL TYPICAL CHARACTERISTICS**

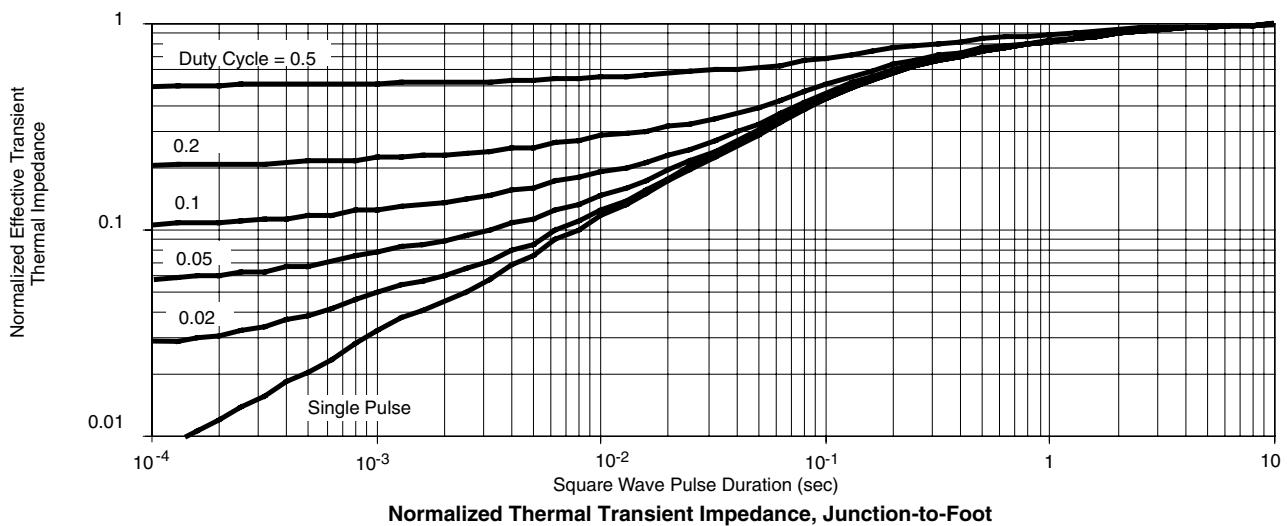
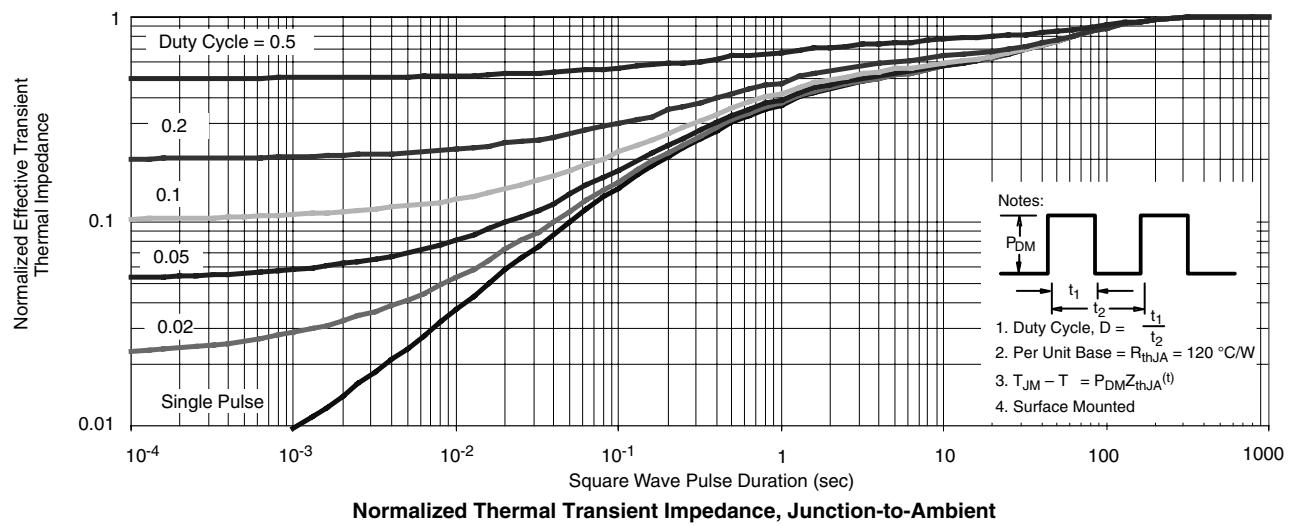
25 °C unless noted



**N-CHANNEL TYPICAL CHARACTERISTICS** 25 °C unless noted

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 $T_C$  – Case Temperature (°C)  
**Current Derating\***

 $T_C$  – Case Temperature (°C)  
**Power Derating, Junction-to-Foot**

 $T_C$  – Case Temperature (°C)  
**Power Derating, Junction-to-Ambient**

\*The power dissipation  $P_D$  is based on  $T_J(\max) = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

**N-CHANNEL TYPICAL CHARACTERISTICS** 25 °C unless noted

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